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[10191/1565]

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants : Volker BECKER et al.
Serial No. : 09/674,984
Filed : January 8, 2001
For : A DEVICE AND METHOD FOR DETERMINING THE
LATERAL UNDERCUT OF A STRUCTURED SURFACE
LAYER
Examiner : William D. Coleman
Group Art Unit : 2823

Commissioner for Patents
Washington, D.C. 20231

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Jong H. Lee

AMENDMENT UNDER 37 C.F.R. § 1.111

SIR:

In response to the non-final Office Action dated May 24, 2002, please amend the above-
identified application as follows:

IN THE CLAIMS:

Please amend claims 23 and 33 as follows:

23. (Amended) A device for determining an extent of an at least locally lateral
undercut of a structured surface layer on a sacrificial layer, comprising:
at least one passive electronic component arranged on the structured surface layer in the shape of a
coil for determining a physical measured quantity that is proportional to the extent of the lateral undercut.

33. (Amended) The device according to claim 23, wherein:
the coil delineated out in the structured surface layer includes a first coil end and a second
coil end,
the coil and a base layer arranged with respect to the structured surface layer and the
sacrificial layer form a capacitor having a capacitance proportional to the extent of the lateral undercut.

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